XJP-403J Series

This series microscope is widely used in observation & analysis of metallurgical organization in the Mechanical industry, Research of Geological & Mineral department and viewing & measuring crystal, integrate circuit, microelectronics, etc in Electronic industry. It is the first choice of Factories, Academy, Scientific research organization contrast image. Novel figure and superior crafts manship keep abreast of the tidal current much more.
Humanized configuration design and simple operation, Let you release from the pressure of heavy work.

Specification			Model			
			XJP-403J	XJP-403JT	XJP-403JA	XJP-403JAT
Viewing head	Compensation Free Binocular Head. Inclined at 45 ° (50mm -75mm)		●		●	
	Compensation Free Trinocular Head. Inclined at 45 ° (50mm -75mm)			●		●
Eyepiece	WF10X/20mm		●	●		
	WF10X/ 22mm				●	●
	WF10X/20mm with reticule 0.1mm		●	●	●	●
Nosepiece	Quadruple nosepiece				●	●
	Quintuple nosepiece		●	●		
Objective	195 metallurgical objectives	4X/0.1W.D.25mm	●	●		
		10X/ 0.25W.D .11mm				
		20X/0.4W.D .9mm				
		40X/0.6W.D. 3.8mm				
	Infinity metallurgical objectives	4X/0.1W.D.25mm			●	●
		10X/ 0.25W.D .12mm				
		20X/0.4W.D .10mm				
		40X/0.6W.D. 7.1mm				
	50X/0.75W.D. 1.9mm 80 (S)X/0.9W.D. 0.9mm		○	○	○	○
Stage	Double layers mechanical stage		●	●	●	●
	Stage size: 242mm × 172mm					
	Central stage: Φ110mm					
	Moving range: 75mm × 50mm					
Focusing	Coaxial coarse & fine focusing adjustment with rack and pinion mechanism Fine focusing scale Value 0.002mm		●	●	●	●
Illumination	Epi-Kohler illumination. With aperture iris diaphragm and field iris diaphragm. 12V/30W.AC85V-230V Adjustable brightness		●	●	●	●
Filter	Blue, green, yellow		●	●	●	●
Polarizing outfit	Analyzer rotatable 360 ° ,polarizer & Analyzer can be slid in/out of the optical path		●	●	●	●
Checking tool	0.01mm micrometer		●	●	●	●
Optional Accessory	1.3、2.0、3.0、5.0 Megapixels CMOS electronic eyepiece					
	Photography attachment					